

# **Notice of References Cited**

Application/Control No.

09/658,732

Applicant(s)/Patent Under Reexam

Inai et al.

Examiner

B. William Baumeister

Art Unit

2815

Page 1 of 1

## **U.S. PATENT DOCUMENTS**

		Document Number Country Code-Number-Kind Code	Date MM-YYYY <sup>1</sup>	Name	Classification <sup>2</sup>
	A				
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## **FOREIGN PATENT DOCUMENTS**

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	N					
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	Q					
	R					
	S					
	T					

## **NON-PATENT DOCUMENTS**

		Include, as applicable: Author, Title, Date, Publisher, Edition or Volume, Pertinent Pages
	U	Enoki, "Delay Time Analysis for 0.4- to 5-micron-Gate InAlAs-InGaAs HEMT's," IEEE Electron Device Letters 11 (1990) November, No. 11, pp. 502-504.
	V	
	W	
	X	

\* A copy of this reference is not being furnished with this Office action. See MPEP § 707.05(a).

<sup>1</sup> Dates in MM-YYYY format are publication dates.

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